PATENT

Claim Amendments:

Please amend the claims as indicated:

Claims 1-18 (Withdrawn)

- 19. (Currently Amended) An electronic package A multi-chip module, comprising:
- a first semiconductor device capable of enabling functionality associated with a first circuit segment of an integrated circuit design and including an array including a set of first device interconnect pads;
- a second semiconductor device capable of enabling functionality associated with a second circuit segment of the integrated circuit design and including an arrayincluding a set of second device interconnect pads; and
- a plurality of device interconnect members, each one of said device interconnect members being electrically connected directly between one of said first device interconnect pads and a corresponding one of said second device interconnect pads.
- 20. (Currently Amended) The <u>electronic package multi-chip module</u> of claim 19 wherein:
 - the first semiconductor device-includes is capable of enabling functionality associated with a first functional block of the integrated circuit design; and the second semiconductor device device is capable of enabling functionality associated
 - with a second functional block of the integrated circuit design.
- 21. (Currently Amended) The <u>electronic package multi-eliip module</u> of claim 19 wherein:

the first semiconductor device is a DRAM device; and the second semiconductor device is a logic device.

22. (Currently Amended) The <u>electronic package</u> multi-ehip module of claim 19 wherein:

the first semiconductor device is made from a first type of semiconductor substrate; and the second semiconductor device is made from a second type of semiconductor substrate.

- 23. (Currently Amended) The <u>electronic package multi-chip module</u> of claim 19 wherein each one of said device interconnect members is a solder-type interconnect member.
- 24. (Currently Amended) The <u>electronic packagemulti-chip module</u> of claim 23 wherein the solder-type interconnect member is a solder bump.
- 25. (Currently Amended) The <u>electronic package multi-ehip module</u> of claim 23 wherein the solder-type interconnect member is a solder ball.
- 26. (Currently Amended) The electronic package of claim 19 wherein the electronic package is a multichip module and the plurality of device interconnect members includes solder-type interconnect members. A multi-chip module, comprising:
 - a first semiconductor device capable of enabling functionality associated with a first functional block of an integrated circuit design and including an array of first device interconnect members;
 - a-second-somiconductor device-capable of enabling functionality associated with a second functional block of the integrated circuit design and including an array of second-device interconnect members; and
 - a-plurality-of-solder-type interconnect-members, each one of said solder-type interconnect members being electrically connected directly between one of said-first device interconnect members and a corresponding one of said second device interconnect members.
- 27. (Currently Amended) The <u>electronic package multi-ehip module</u> of claim 26 wherein:

the first semiconductor device is a DRAM device; and the second semiconductor device is a logic device.

PATENT

28. (Currently Amended) The <u>electronic packagemulti-chip module</u> of claim 26 wherein:

the first semiconductor device is made from a first type of semiconductor substrate; and the second semiconductor device is made from a second type of semiconductor substrate.

- 29. (Currently Amended) The <u>electronic package multi-chip-module</u> of claim 26 wherein the solder-type interconnect member is a solder bump.
- 30. (Currently Amended) The <u>electronic package multi-chip module</u> of claim 26 wherein the solder-type interconnect member is a solder ball.
- 31. (Currently Amended) An electronic package, The electronic package of claim 19, further comprising:
 - an interposer circuit including a dielectric substrate and an array of routing elements attached to the dielectric substrate; and
 - a first semiconductor device capable of enabling functionality associated with a first circuit segment of an integrated circuit design-and-including an array of first device interconnect pads;
 - a second the second semiconductor device capable of enabling functionality associated with a second circuit segment of the integrated circuit design, including an array of-second device interconnect pads and including further comprising a set of package-level interconnect pads; and
 - a plurality of device interconnect members, each one of said device interconnect
 members being electrically connected directly between one of the said-first device
 interconnect pads-and a corresponding one of said-second device interconnect
 pads: and
 - a plurality of package-level interconnect members, each one of said package-level interconnect members being electrically connected between one of the said package-level interconnect pads of the second semiconductor device and a corresponding one of said routing elements of the interposer circuit.
 - 32. (Original) The electronic package of claim 31 wherein:

PATENT

the first semiconductor device includes is capable of enabling functionality associated with a first functional block of the integrated circuit design; and the second semiconductor device is capable of enabling functionality associated with a second functional block of the integrated circuit design.

- 33. (Original) The electronic package of claim 31 wherein: the first semiconductor device is a DRAM device; and the second semiconductor device is a logic device.
- 34. (Original) The electronic package of claim 31 wherein: the first semiconductor device is made from a first type of semiconductor substrate; and the second semiconductor device is made from a second type of semiconductor substrate.
- 35. (Original) The electronic package of claim 31 wherein each one of said device interconnect members is a solder-type interconnect member.
- 36. (Original) The electronic package of claim 35 wherein the solder-type interconnect member is a solder bump.
- 37. (Original) The electronic package of claim 35 wherein the solder-type interconnect member is a solderball.
 - 38. (Original) The electronic package of claim 31 wherein: the interposer circuit is a flip-chip interposer circuit; and each one of said package-level interconnect members is a solder-type interconnect member.
 - 39. (Original) The electronic package of claim 31 wherein: the interposer circuit is a wire-bond interposer circuit; and each one of said package-level interconnect members is a conductive wire.
 - 40. (Canceled)

41. (Currently Amended) The electronic package of claim 35 elaim 40 wherein: the first semiconductor device is a DRAM device; and the second semiconductor device is a logic device.

TOLER LARSON ABEL

- 42. (Currently Amended) The electronic package of claim 35 elaim 40 wherein: the first semiconductor device is made from a first type of semiconductor substrate; and the second semiconductor device is made from a second type of semiconductor substrate.
- 43. (Currently Amended) The electronic package of claim 35claim 40 wherein the solder-type interconnect member is a solder bump.
- 44. (Currently Amended) The electronic package of elaim 40claim 35 wherein the solder-type interconnect member is a solder ball.
 - 45. (Currently Amended) The electronic package of elaim 40 claim 35 wherein: the interposer circuit is a flip-chip interposer circuit; and each one of said package-level interconnect members is a solder-type interconnect member.
 - 46. (Currently Amended) The electronic package of elaim 40 claim 35 wherein: the interposer circuit is a wire-bond interposer circuit; and each one of said package-level interconnect members is a conductive wire.